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CONTINUING DATA

REIGN APPLICATIONS ***
JAPAN 2000-183104 08/27/2000
JAPAN 2000-228101 07/28/2000
JAPAN 2000-315834 11/02/2000
JAPAN 2001-11218 01/18/2001
JAPAN 2001-31901 02/08/2001
JAPAN 2001-31802 02/08/2001
JAPAN 2001-33598 02/09/2001
JAPAN 2001-35088 02/13/2001
JAPAN 2001-58828 03/28/2001
JAPAN 2001-162041 05/30/2001
JAPAN 2001-189304 09/22/2001

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Inspection system by charged particle beam and method of manufacturing devices using the system

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